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1	We claim:
2	1. A method for annealing a structure formed by electrodeposition, the
3	method comprising:
4	providing the electrodeposition structure, the electrodeposition structure
5	comprising an electroformed mold, the electroformed mold having a nominal thickness
6	between and including 0.5mm to 8.0mm and having a melting temperature;
7	heating the electrodeposition structure to a temperature between ambient
8	temperature and the melting temperature of the electrodeposition structure;
9	isostatically pressurizing the electrodeposition structure to a pressure above
10	ambient pressure;
11	cooling the electrodeposition structure to ambient temperature; and
12	depressurizing the electrodeposition structure to ambient pressure.
13	2. An electroformed mold, the electroformed mold annealed at an annealing
14	temperature above ambient temperature and an annealing pressure above ambient
15	pressure; and
16	the electroformed mold comprising a material having an elongation measured at
l <i>7</i>	break before and after annealing, the elongation at break after annealing being greater
18	than the elongation at break before annealing.
19	3. An electroformed mold, the electroformed mold comprising a material
20	having voids therein, at least a portion of the voids forming at least one protuberance on

the surface of the electroformed mold when the mold is exposed to heat;

1	the electroformed mold annealed at an annealing temperature above ambient
2	temperature and an annealing pressure above ambient pressure; and
3	the number of voids forming protuberances on the surface of the electroformed
4	mold being reduced after annealing of the electroformed mold as compared to before
5	annealing of the electroformed mold.
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